Message from STA 2009 Workshop Co-chairs

Welcome to the 1st IEEE International Workshop on Software Test Automation (STA 2009). STA 2009 is to be held in conjunction with The 33rd IEEE Computer Society Signature Conference on Computer, Software and Applications (COMPSAC 2009) in Seattle, US on July 24, 2009. On behalf of the program committee, we welcome you to Seattle, USA.

A significant percentage of time and effort in software development is spent on testing and yet the achieved quality is less than desired. To reduce cost and improve quality, test automation solutions are necessary. To facilitate the discussion on this important area, we have introduced this year a new workshop on “Software Test Automation 2009”. The workshop provides an opportunity for academic researchers and industry participants and practitioners to exchange ideas, experiences, understand problems in theory and practice, and lay a foundation for the future in the area of test automation.

We seek discussion on topic including but not restricted to various test automation techniques and methods, tool interoperability, automation in different development lifecycle methodologies, support for test methods, application in different domains, test tools and environments, experiments and empirical studies and visions of the future.

We were fortunate to receive some high quality papers from diverse background. With prompt help of our reviewers, we were able to select 5 papers in addition to an invited keynote speaker. We would like to thank all the reviewers and program committee members for their thoughtful comments and help in selecting the papers.

We thank all the authors for sharing their ideas and results with us, and all the members of the Program Committee and reviewers for their help in evaluating and selecting high quality papers. We owe to them for the success of the workshop. Our thanks to COMPSAC 2009 general chair, Carl Chang, workshop chair Iqbal Sheikh, and program co-chairs Drs. Lin Liu, Vladimir, and Elisa Bertino for their help and encouragement.

We thank you in anticipation of your active participation and hope that you will equally enjoy the workshop and your stay in Seattle.

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